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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, EBI/EMI, I ² C, MMC/SD, QSPI, SCI, SSIE, SPI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	84
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	192K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 25x14b; D/A 2x8b, 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LFQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a17c3a01cfp-aa0

1. Overview

The MCU integrates multiple series of software- and pin-compatible Arm®-based 32-bit MCUs that share a common set of Renesas peripherals to facilitate design scalability and efficient platform-based product development.

The MCU provides an optimal combination of low-power, high-performance Arm Cortex®-M4 core running up to 48 MHz, with the following features:

- 1-MB code flash memory
- 192-KB SRAM
- Segment LCD Controller (SLCDC)
- Capacitive Touch Sensing Unit (CTSU)
- USB 2.0 Full-Speed Module (USBFS)
- 14-bit A/D Converter (ADC14)
- 12-bit D/A Converter (DAC12)
- Security features.

1.1 Function Outline

Table 1.1 Arm core

Feature	Functional description
Arm Cortex-M4	• Maximum operating frequency: up to 48 MHz • Arm Cortex-M4 - Revision: r0p1-01rel0 - Armv7E-M architecture profile - Single precision floating-point unit compliant with the ANSI/IEEE Std 754-2008. • Arm Memory Protection Unit (Arm MPU) - Armv7 Protected Memory System Architecture - 8 protect regions. • SysTick timer - Driven by SYSTICCLK (LOCO) or ICLK.

Table 1.2 Memory

Feature	Functional description
Code flash memory	Maximum 1-MB code flash memory. See section 47, Flash Memory in User's Manual.
Data flash memory	8-KB data flash memory. See section 47, Flash Memory in User's Manual.
Option-setting memory	The option-setting memory determines the state of the MCU after a reset. See section 7, Option-Setting Memory in User's Manual.
Memory Mirror Function (MMF)	The MMF can be configured to mirror the target application image load address in code flash memory to the application image link address in the 23-bit unused memory space (memory mirror space addresses). Your application code is developed and linked to run from this MMF destination address. The application code does not need to know the load location where it is stored in code flash memory. See section 5, Memory Mirror Function (MMF) in User's Manual.
SRAM	On-chip high-speed SRAM with either parity bit or Error Correction Code (ECC). The first 16-KB in SRAM0 provides error correction capability using ECC. See section 46, SRAM in User's Manual.

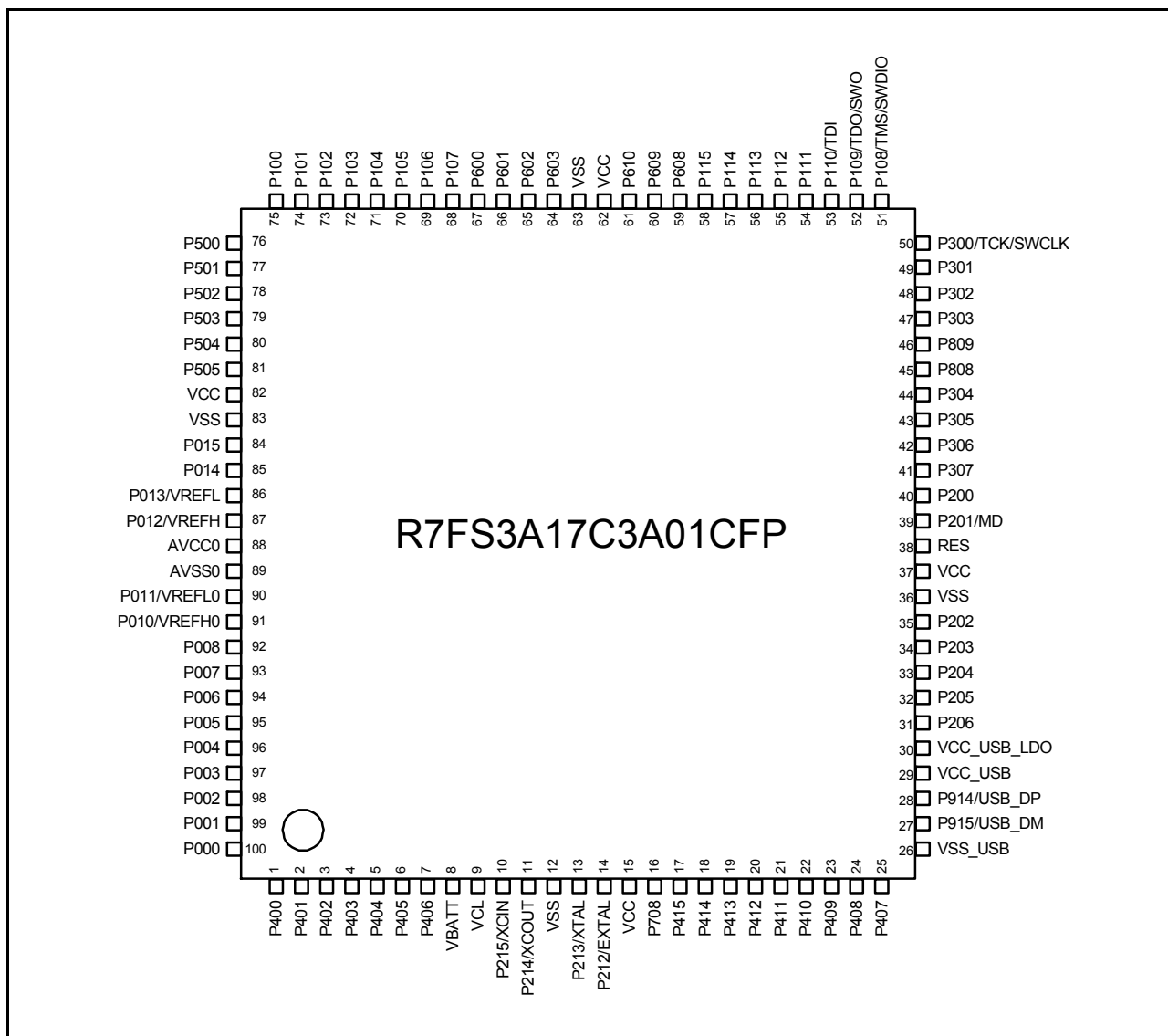


Figure 1.6 Pin assignment for 100-pin LQFP (top view)

2.2.4 I/O V_{OH} , V_{OL} , and Other Characteristics**Table 2.7** I/O V_{OH} , V_{OL} (1)Conditions: $V_{CC} = AVCC0 = VCC_USB = VCC_USB_LCO = 4.0$ to 5.5 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	IIC*1	V_{OL}	-	-	0.4	V	$I_{OL} = 3.0$ mA
		$V_{OL}^{*2, *5}$	-	-	0.6		$I_{OL} = 6.0$ mA
	Ports P408, P409*2, *3	V_{OH}	$VCC - 1.0$	-	-		$I_{OH} = -20$ mA
		V_{OL}	-	-	1.0		$I_{OL} = 20$ mA
	Ports P000 to P015	Low drive	V_{OH}	$AVCC0 - 0.8$	-		$I_{OH} = -2.0$ mA
			V_{OL}	-	0.8		$I_{OL} = 2.0$ mA
		Middle drive	V_{OH}	$AVCC0 - 0.8$	-		$I_{OH} = -4.0$ mA
			V_{OL}	-	0.8		$I_{OL} = 4.0$ mA
	Ports P914, P915	V_{OH}	$VCC_USB - 0.8$	-	-		$I_{OH} = -2.0$ mA
		V_{OL}	-	-	0.8		$I_{OL} = 2.0$ mA
	Other output pins*4	Low drive	V_{OH}	$VCC - 0.8$	-		$I_{OH} = -2.0$ mA
			V_{OL}	-	0.8		$I_{OL} = 2.0$ mA
		Middle drive*6	V_{OH}	$VCC - 0.8$	-		$I_{OH} = -4.0$ mA
			V_{OL}	-	0.8		$I_{OL} = 4.0$ mA

Note 1. P100, P101, P204, P205, P206, P400, P401, P407, P408, P511, P512 (total 11 pins).

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 3. Based on characterization data, not tested in production.

Note 4. Except for ports P200, P214, P215, which are input ports.

Note 5. This is the value when middle driving ability for IIC is selected with the Port Drive Capability bit in PmnPFS register for P408.

Note 6. Except for P212, P213.

Table 2.8 I/O V_{OH} , V_{OL} (2)Conditions: $V_{CC} = AVCC0 = VCC_USB = VCC_USB_LCO = 2.7$ to 4.0 V

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	IIC*1	V_{OL}	-	-	0.4	V	$I_{OL} = 3.0$ mA
		$V_{OL}^{*2, *5}$	-	-	0.6		$I_{OL} = 6.0$ mA
	Ports P408, P409*2, *3	V_{OH}	$VCC - 1.0$	-	-		$I_{OH} = -20$ mA $VCC = 3.3$ V
		V_{OL}	-	-	1.0		$I_{OL} = 20$ mA $VCC = 3.3$ V
	Ports P000 to P015	Low drive	V_{OH}	$AVCC0 - 0.5$	-		$I_{OH} = -1.0$ mA
			V_{OL}	-	0.5		$I_{OL} = 1.0$ mA
		Middle drive	V_{OH}	$AVCC0 - 0.5$	-		$I_{OH} = -2.0$ mA
			V_{OL}	-	0.5		$I_{OL} = 2.0$ mA
	Ports P914, P915	V_{OH}	$VCC_USB - 0.5$	-	-		$I_{OH} = -1.0$ mA
		V_{OL}	-	-	0.5		$I_{OL} = 1.0$ mA
	Other output pins*4	Low drive	V_{OH}	$VCC - 0.5$	-		$I_{OH} = -1.0$ mA
			V_{OL}	-	0.5		$I_{OL} = 1.0$ mA
		Middle drive*6	V_{OH}	$VCC - 0.5$	-		$I_{OH} = -2.0$ mA
			V_{OL}	-	0.5		$I_{OL} = 2.0$ mA

Note 1. P100, P101, P204, P205, P206, P400, P401, P407, P408, P511, P512 (total 11 pins).

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 3. Based on characterization data, not tested in production.

Note 4. Except for ports P200, P214, P215, which are input ports.

Note 5. This is the value when middle driving ability for IIC is selected with the Port Drive Capability bit in PmnPFS register for P408.

Note 6. Except for P212, P213.

Table 2.9 I/O V_{OH} , V_{OL} (3)Conditions: $VCC = AVCC0 = VCC_USB = VCC_USB_LCO = 1.6$ to 2.7 V

Parameter			Symbol	Min	Typ	Max	Unit	Test conditions
Output voltage	Ports P000 to P015	Low drive	V_{OH}	$AVCC0 - 0.3$	-	-	V	$I_{OH} = -0.5$ mA
			V_{OL}	-	-	0.3		$I_{OL} = 0.5$ mA
		Middle drive	V_{OH}	$AVCC0 - 0.3$	-	-		$I_{OH} = -1.0$ mA
			V_{OL}	-	-	0.3		$I_{OL} = 1.0$ mA
	Ports P914, P915		V_{OH}	$VCC_USB - 0.3$	-	-		$I_{OH} = -0.5$ mA
			V_{OL}	-	-	0.3		$I_{OL} = 0.5$ mA
	Other output pins*1	Low drive	V_{OH}	$VCC - 0.3$	-	-		$I_{OH} = -0.5$ mA
			V_{OL}	-	-	0.3		$I_{OL} = 0.5$ mA
		Middle drive*2	V_{OH}	$VCC - 0.3$	-	-		$I_{OH} = -1.0$ mA
			V_{OL}	-	-	0.3		$I_{OL} = 1.0$ mA

Note 1. Except for ports P200, P214, P215, which are input ports.

Note 2. Except for P212, P213.

Table 2.10 I/O other characteristicsConditions: $VCC = AVCC0 = 1.6$ to 5.5 V

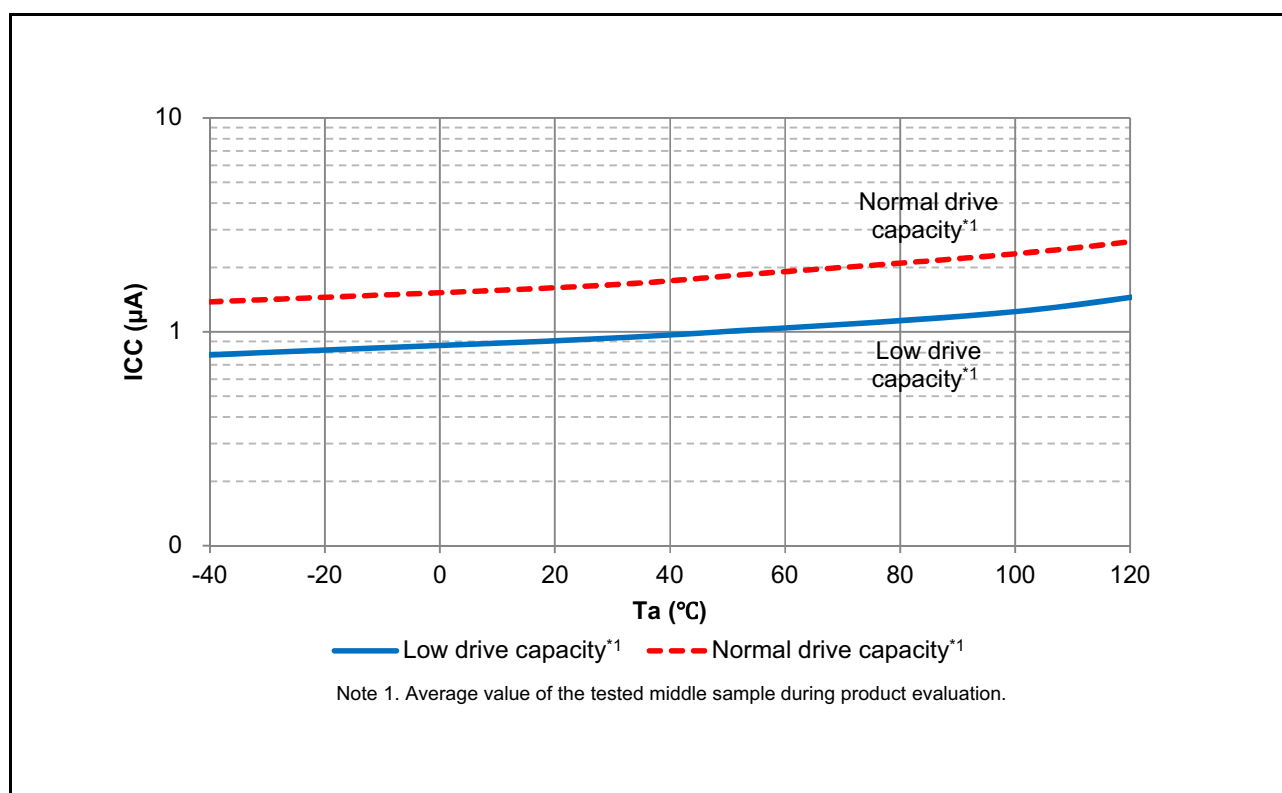
Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Input leakage current	RES, P200, P214, P215	$ I_{in} $	-	-	1.0	μ A	$V_{in} = 0$ V $V_{in} = VCC$
Three-state leakage current (off state)	5V-tolerant ports	$ I_{TSI} $	-	-	1.0	μ A	$V_{in} = 0$ V $V_{in} = 5.8$ V
	Other ports (except for ports P200, P214, P215 and 5 V tolerant)		-	-	1.0		$V_{in} = 0$ V $V_{in} = VCC$
Input pull-up resistor	All ports (except for ports P200, P214, P215, P914, P915)	R_U	10	20	50	k Ω	$V_{in} = 0$ V
Input capacitance	P914, P915, P100 to P103, P111, P112, P200	C_{in}	-	-	30	pF	$V_{in} = 0$ V $f = 1$ MHz $T_a = 25^\circ$ C
	Other input pins		-	-	15		

Table 2.13 Operating and standby current (3)

Conditions: VCC = AVCC0 = 0 V, VBATT = 1.6 to 3.6 V, VSS = AVSS0 = 0 V

Parameter	Symbol	Typ	Max	Unit	Test conditions
Supply current*1 RTC operation when VCC is off	I_{CC}	0.8	-	μA	VBATT = 2.0 V SOMCR.SORDRV[1:0] = 11b (Low power mode 3)
		0.9	-		
		1.1	-		
		1.2	-		
		0.9	-		VBATT = 3.3 V SOMCR.SORDRV[1:0] = 11b (Low power mode 3)
		1.0	-		
		1.2	-		
		1.3	-		
		1.6	-		VBATT = 2.0 V SOMCR.SORDRV[1:0] = 00b (Normal mode)
		1.8	-		
		2.1	-		
		2.3	-		
		1.7	-		VBATT = 3.3 V SOMCR.SORDRV[1:0] = 00b (Normal mode)
		1.9	-		
		2.2	-		
		2.4	-		

Note 1. Supply current values do not include output charge/discharge current from all pins. The values apply when internal pull-up MOSs are in the off state.

**Figure 2.24 Temperature dependency of RTC operation with VCC off (reference data)**

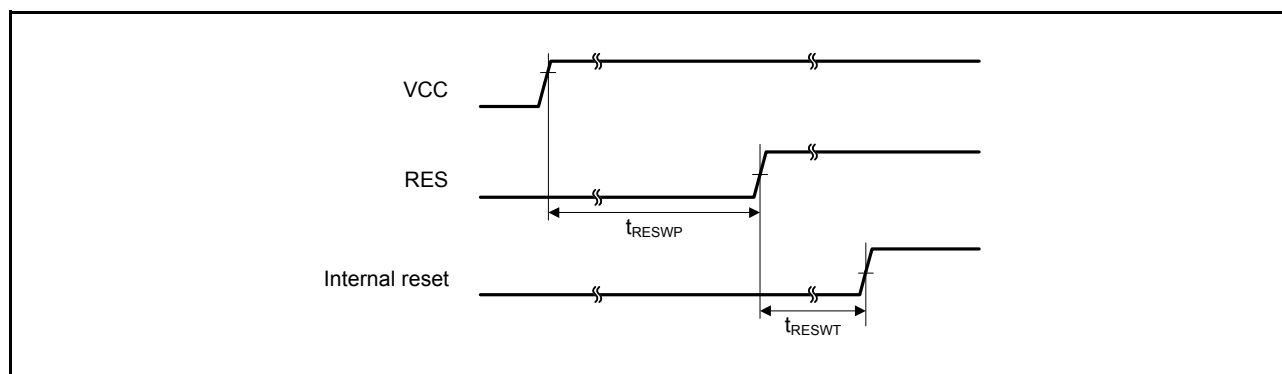
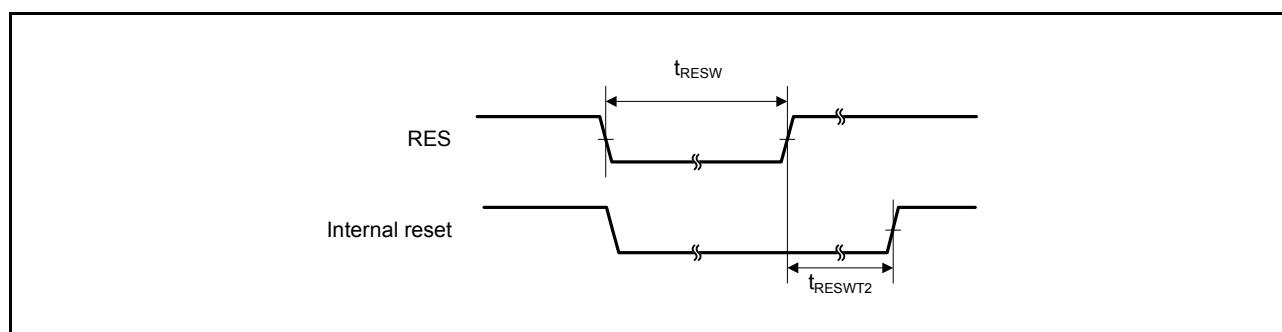
2.3.3 Reset Timing

Table 2.23 Reset timing

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
RES pulse width	At power-on	t_{RESWP}	3	-	-	ms	Figure 2.34
	Other than above	t_{RESW}	30	-	-	μ s	Figure 2.35
Wait time after RES cancellation (at power-on)	LVD0: enable*1	t_{RESWT}	-	0.7	-	ms	Figure 2.34
	LVD0: disable*2		-	0.3	-		
Wait time after RES cancellation (during powered-on state)	LVD0: enable*1	t_{RESWT2}	-	0.5	-	ms	Figure 2.35
	LVD0: disable*2		-	0.05	-		
Internal reset cancellation time (Watchdog timer reset, SRAM parity error reset, SRAM ECC error reset, Bus master MPU error reset, Bus slave MPU error reset, Stack pointer error reset, Software reset)	LVD0: enable*1	t_{RESWT3}	-	0.6	-	ms	
	LVD0: disable*2		-	0.15	-		

Note 1. When OFS1.LVDAS = 0.

Note 2. When OFS1.LVDAS = 1.


Figure 2.34 Reset input timing at power-on

Figure 2.35 Reset input timing (1)

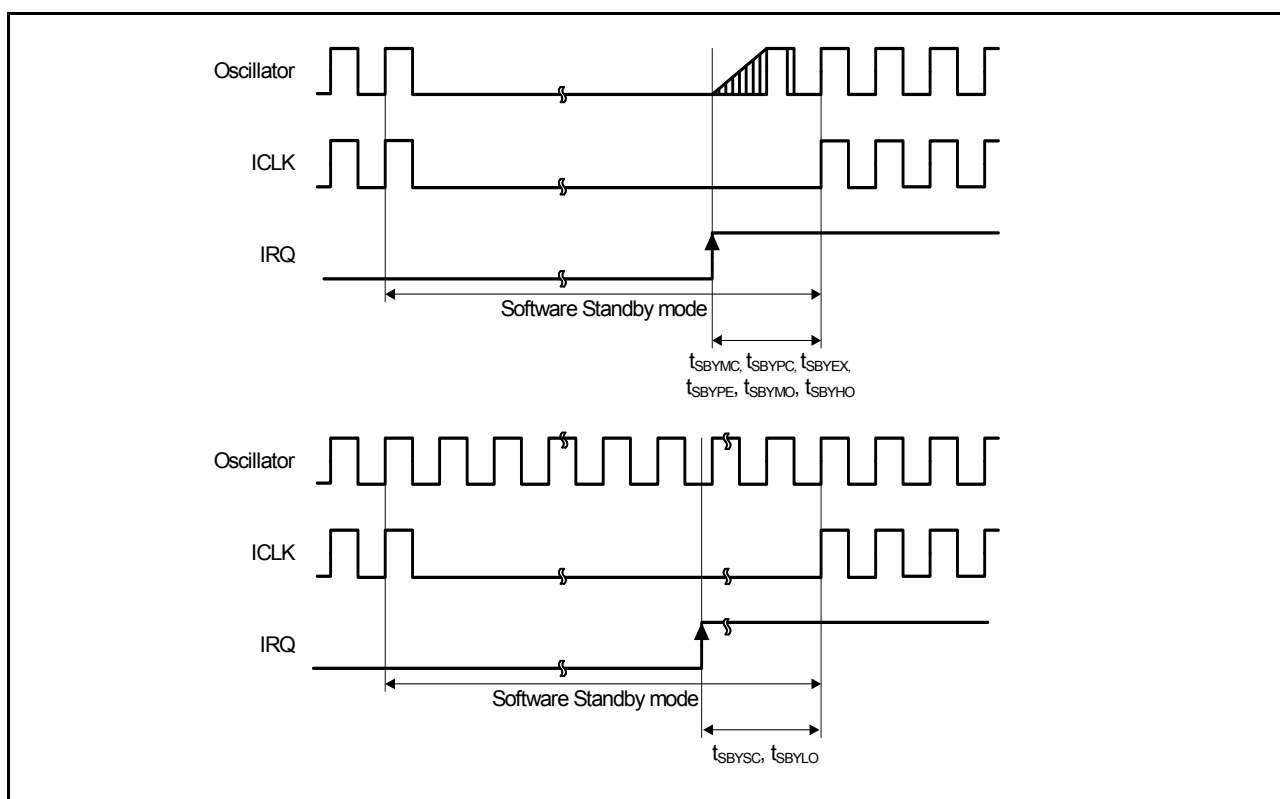


Figure 2.36 Software Standby mode cancellation timing

Table 2.29 Timing of recovery from low power modes (6)

Parameter		Symbol	Min	Typ	Max	Unit	Test conditions
Recovery time from Software Standby mode to Snooze mode	High-speed mode System clock source is HOCO	t_{SNZ}	-	36	45	μs	Figure 2.37
	Middle-speed mode System clock source is MOCO	t_{SNZ}	-	1.3	3.6	μs	
	Low-speed mode System clock source is MOCO	t_{SNZ}	-	10	13	μs	
	Low-voltage mode System clock source is HOCO	t_{SNZ}	-	87	110	μs	

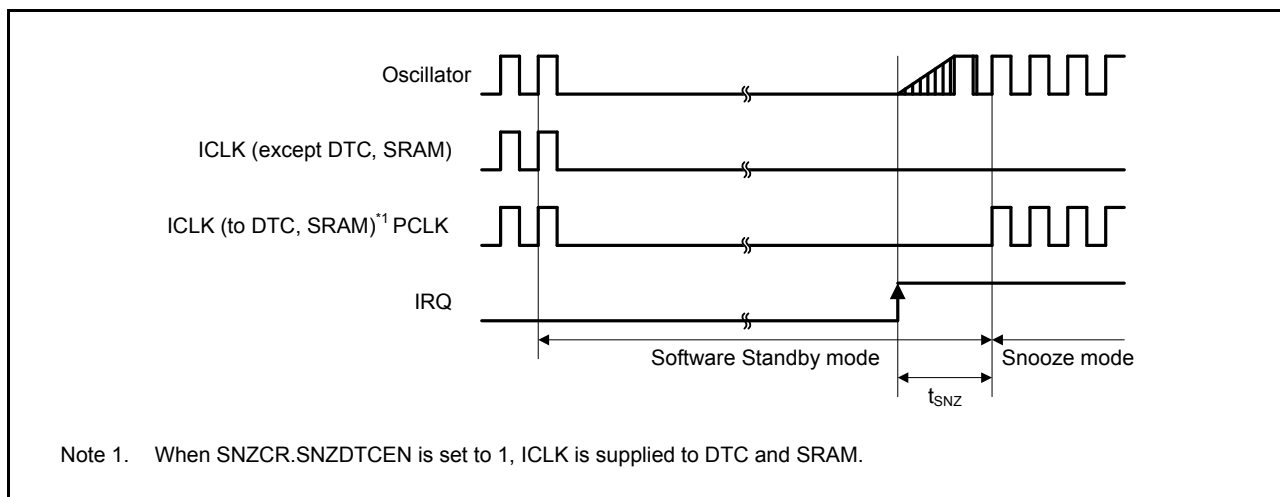
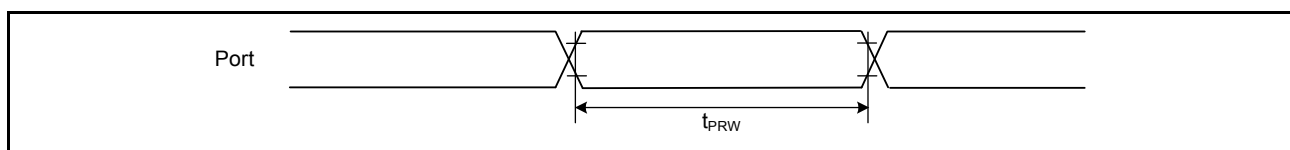
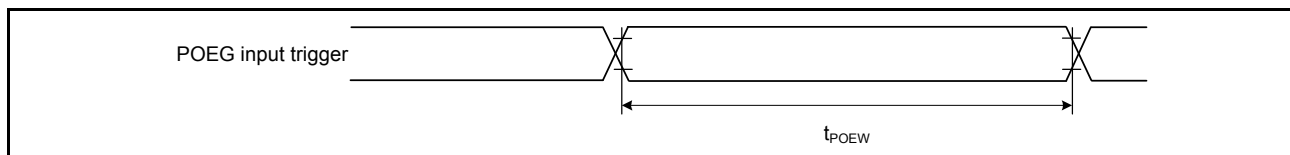
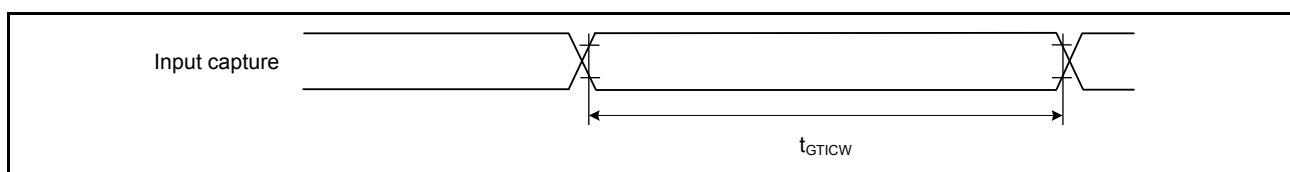


Figure 2.37 Recovery timing from Software Standby mode to Snooze mode

2.3.7 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 Trigger Timing

Table 2.35 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 trigger timing

Parameter			Symbol	Min	Max	Unit	Test conditions
I/O ports	Input data pulse width		t _{PRW}	1.5	-	t _{Pcyc}	Figure 2.47
	Input/output data cycle (P002, P003, P004, P007)		t _{POcyc}	10	-	us	
POEG	POEG input trigger pulse width		t _{POEW}	3	-	t _{Pcyc}	Figure 2.48
GPT	Input capture pulse width	Single edge	t _{GTICW}	1.5	-	t _{PDcyc}	Figure 2.49
		Dual edge		2.5	-		
AGT	AGTIO, AGTEE input cycle	2.7 V ≤ VCC ≤ 5.5 V	t _{ACYC} *1	250	-	ns	Figure 2.50
		2.4 V ≤ VCC < 2.7 V		500	-	ns	
		1.8 V ≤ VCC < 2.4 V		1000	-	ns	
		1.6 V ≤ VCC < 1.8 V		2000	-	ns	
	AGTIO, AGTEE input high level width, low-level width	2.7 V ≤ VCC ≤ 5.5 V	t _{ACKWH} , t _{ACKWL}	100	-	ns	Figure 2.50
		2.4 V ≤ VCC < 2.7 V		200	-	ns	
		1.8 V ≤ VCC < 2.4 V		400	-	ns	
		1.6 V ≤ VCC < 1.8 V		800	-	ns	
	AGTIO, AGTO, AGTOA, AGTOB output cycle	2.7 V ≤ VCC ≤ 5.5 V	t _{ACYC2}	62.5	-	ns	Figure 2.50
		2.4 V ≤ VCC < 2.7 V		125	-	ns	
		1.8 V ≤ VCC < 2.4 V		250	-	ns	
		1.6 V ≤ VCC < 1.8 V		500	-	ns	
ADC14	14-bit A/D converter trigger input pulse width		t _{TRGW}	1.5	-	t _{Pcyc}	Figure 2.51
KINT	KRn (n = 00 to 07) pulse width		t _{KR}	250	-	ns	Figure 2.52

Note 1. Constraints on AGTIO input: $t_{Pcyc} \times 2 < t_{ACYC}$ Note: t_{Pcyc} : PCLKB cycle, t_{PDcyc} : PCLKD cycle**Figure 2.47 I/O ports input timing****Figure 2.48 POEG input trigger timing****Figure 2.49 GPT input capture timing**

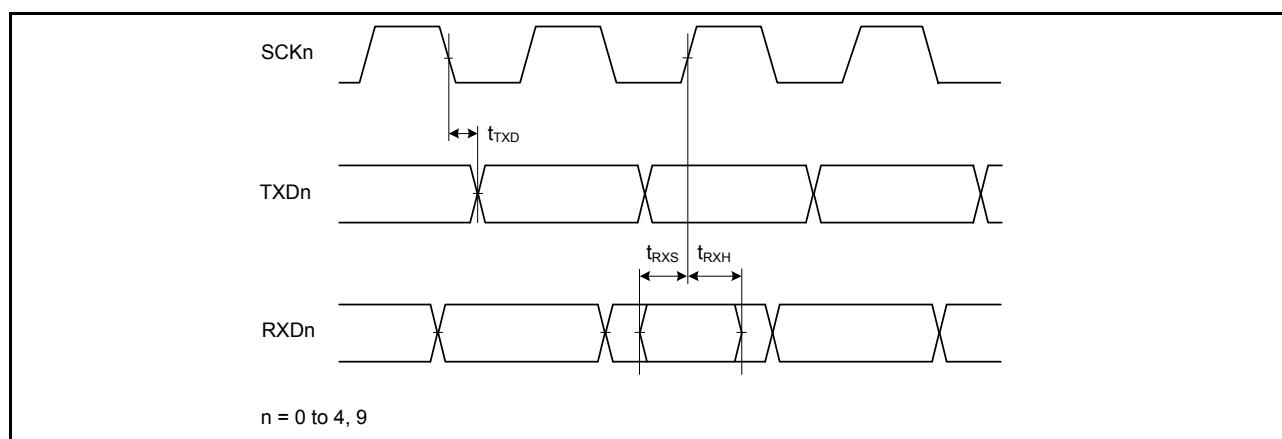


Figure 2.54 SCl input/output timing in clock synchronous mode

Table 2.38 SCl timing (2) (1 of 2)

Parameter				Symbol	Min	Max	Unit	Test conditions	
Simple SPI	SCK clock cycle output (master)			t_{SPcyc}	4	65536	t_{Pcyc}	Figure 2.55	
	SCK clock cycle input (slave)				6	65536			
	SCK clock high pulse width			t_{SPCKWH}	0.4	0.6	t_{SPcyc}		
	SCK clock low pulse width			t_{SPCKWL}	0.4	0.6	t_{SPcyc}		
	SCK clock rise and fall time		1.8 V or above	$t_{SPCKr},$ t_{SPCKf}	-	20	ns		
			1.6 V or above		-	30			
	Data input setup time		Master	2.7 V or above	t_{SU}	45	-	ns	Figure 2.56 to Figure 2.59
				2.4 V or above		55	-		
				1.8 V or above		80	-		
				1.6 V or above		110	-		
Slave			2.7 V or above	40		-			
			1.6 V or above	45		-			
Data input hold time		Master		t_H	33.3	-	ns		
		Slave			40	-			
SS input setup time				t_{LEAD}	1	-	t_{SPcyc}		
SS input hold time				t_{LAG}	1	-	t_{SPcyc}		
Data output delay		Master	1.8 V or above	t_{OD}	-	40	ns		
			1.6 V or above		-	50			
		Slave	2.4 V or above		-	65			
			1.8 V or above		-	100			
			1.6 V or above		-	125			
Data output hold time		Master	2.7 V or above		t_{OH}	-10		-	ns
			2.4 V or above	-20		-			
			1.8 V or above	-30		-			
			1.6 V or above	-40		-			
		Slave		-10		-			
		Data rise and fall time		Master		1.8 V or above	t_{Dr}, t_{Df}	-	
1.6 V or above	-				30				
Slave	1.8 V or above			-	20				
	1.6 V or above			-	30				

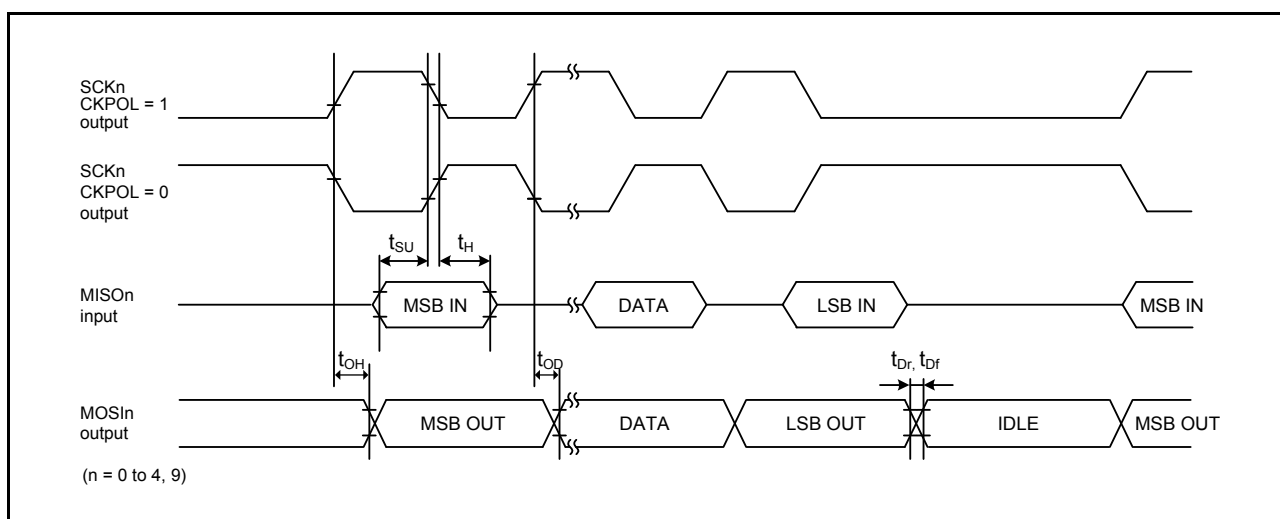


Figure 2.57 SCI simple SPI mode timing (master, CKPH = 0)

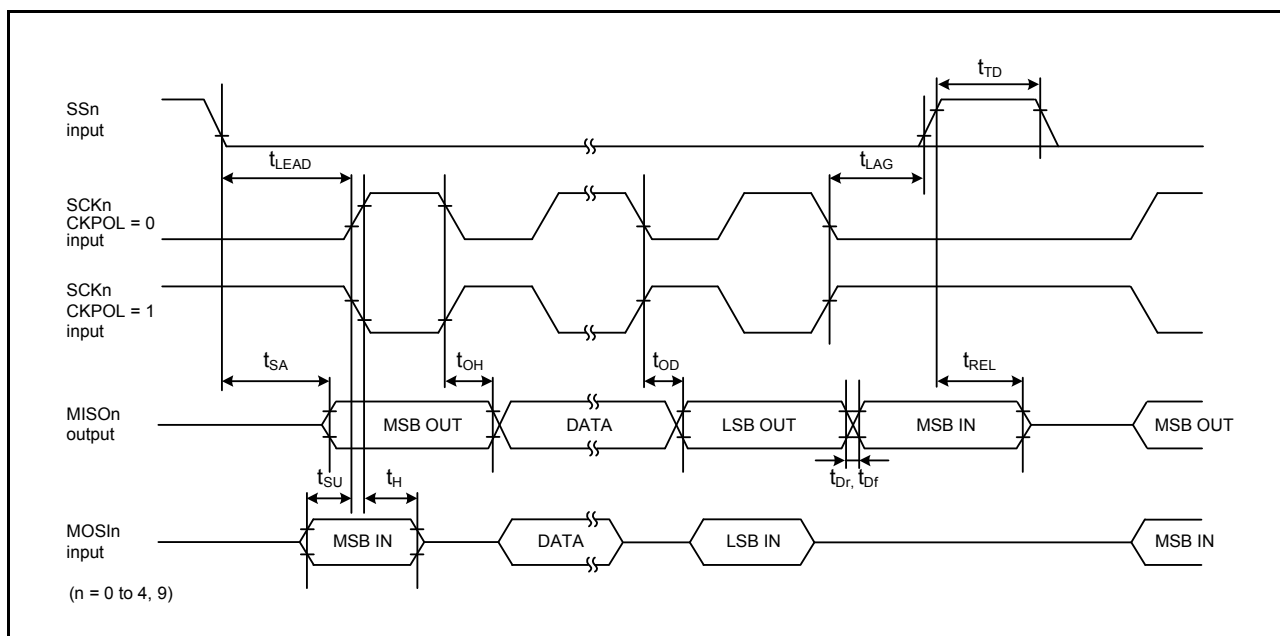


Figure 2.58 SCI simple SPI mode timing (slave, CKPH = 1)

2.3.10 SPI Timing

Table 2.40 SPI timing (1 of 2)

Conditions: Middle drive output is selected in the Port Drive Capability in PmnPFS register

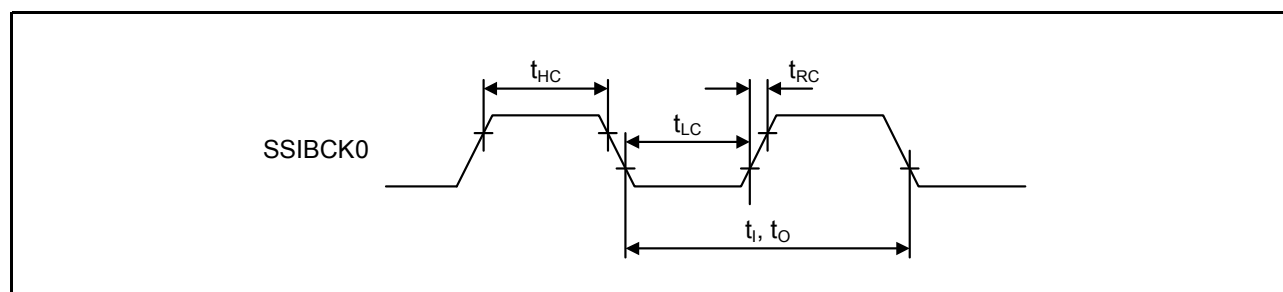
Parameter				Symbol	Min	Max	Unit*1	Test conditions
SPI	RSPCK clock cycle	Master		t_{SPCyc}	2*4	4096	t_{Pcyc}	Figure 2.61
		Slave			6	4096		
	RSPCK clock high pulse width	Master		t_{SPCKWH}	$(t_{SPCyc} - t_{SPCKr} - t_{SPCKf}) / 2 - 3$	-	ns	
		Slave			$3 \times t_{Pcyc}$	-		
	RSPCK clock low pulse width	Master		t_{SPCKWL}	$(t_{SPCyc} - t_{SPCKr} - t_{SPCKf}) / 2 - 3$	-	ns	
		Slave			$3 \times t_{Pcyc}$	-		
	RSPCK clock rise and fall time	Output	2.7 V or above	t_{SPCKr}, t_{SPCKf}	-	10	ns	
			2.4 V or above		-	15		
			1.8 V or above		-	20		
			1.6 V or above		-	30		
		Input		-	1	μs		
	Data input setup time	Master		t_{SU}	10	-	ns	Figure 2.62 to Figure 2.67
		Slave	2.4 V or above		10	-		
			1.8 V or above		15	-		
			1.6 V or above		20	-		
	Data input hold time	Master (RSPCK is PCLKA/2)		t_{HF}	0	-	ns	
		Master (RSPCK is other than above.)		t_H	t_{Pcyc}	-		
Slave		t_H	20	-				
SSL setup time	Master	1.8 V or above	t_{LEAD}	$-30 + N \times t_{Spcyc}^{*2}$	-	ns		
		1.6 V or above		$-50 + N \times t_{Spcyc}^{*2}$	-			
	Slave			$6 \times t_{Pcyc}$	-			
SSL hold time	Master		t_{LAG}	$-30 + N \times t_{Spcyc}^{*3}$	-			
	Slave			$6 \times t_{Pcyc}$	-			

2.3.13 SSIE Timing

Table 2.43 SSIE timing

Conditions: VCC = 1.6 to 5.5 V

Parameter			Symbol	Min	Max	Unit	Test conditions
SSIE	AUDIO_CLK input frequency	2.7 V or above	t_{AUDIO}	-	25	MHz	-
		1.6 V or above		-	4		
	Output clock period		t_{O}	250	-	ns	Figure 2.71
	Input clock period		t_{I}	250	-	ns	
	Clock high pulse width	1.8 V or above	t_{HC}	100	-	ns	
		1.6 V or above		200	-		
	Clock low pulse width	1.8 V or above	t_{LC}	100	-	ns	
		1.6 V or above		200	-		
	Clock rise time		t_{RC}	-	25	ns	
	Data delay	2.7 V or above	t_{DTR}	-	65	ns	Figure 2.72, Figure 2.73
		1.8 V or above		-	105		
		1.6 V or above		-	140		
	Set-up time	2.7 V or above	t_{SR}	65	-	ns	
		1.8 V or above		90	-		
1.6 V or above		140		-			
Hold time		t_{HTR}	40	-	ns		
SSITXD0 output delay from SSILRCK/SSIFS change time	1.8 V or above	t_{DTRW}	-	105	ns	Figure 2.74	
	1.6 V or above		-	140			

**Figure 2.71 SSIE clock input/output timing**

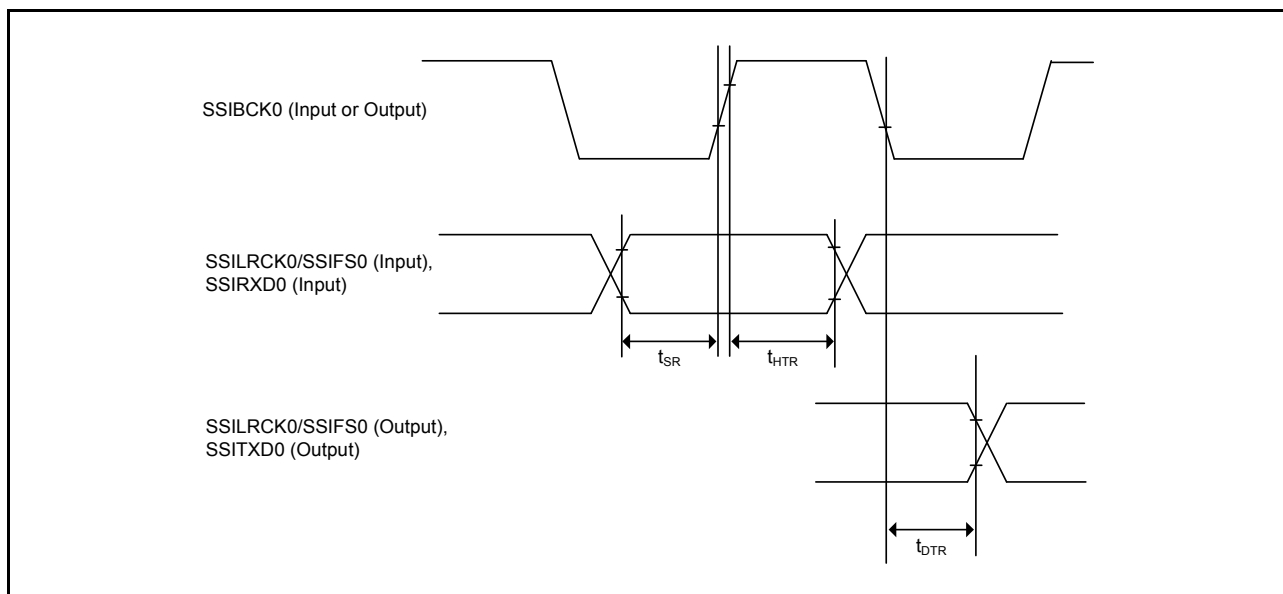


Figure 2.72 SSIE data transmit/receive timing (SSICR.BCKP = 0)

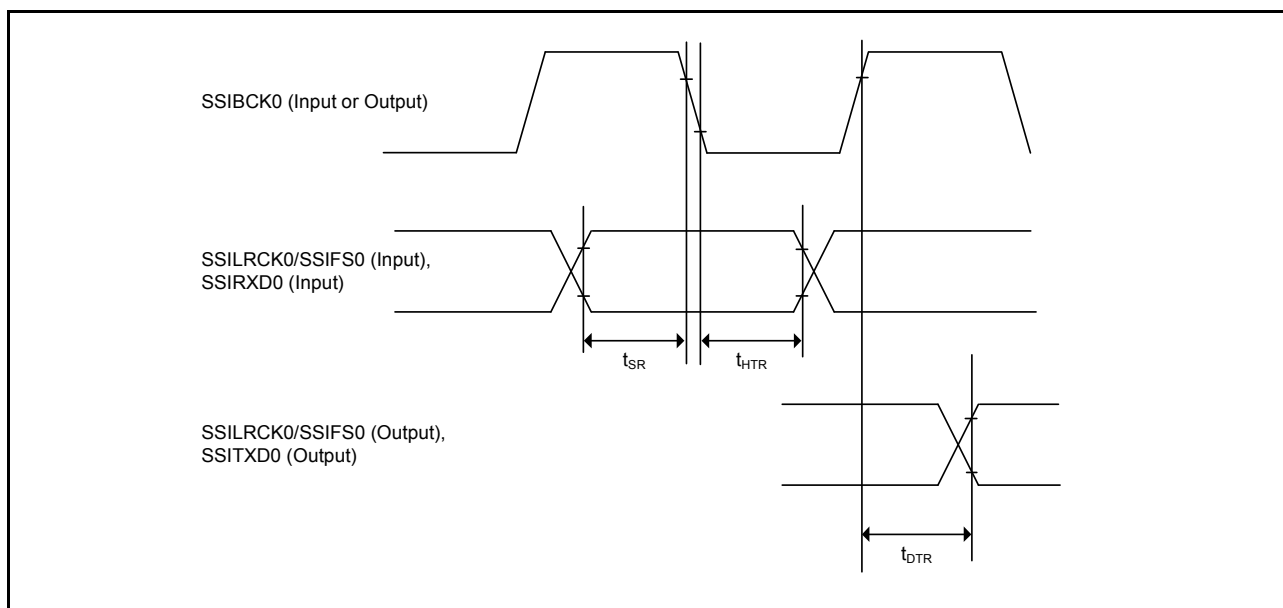


Figure 2.73 SSIE data transmit/receive timing (SSICR.BCKP = 1)

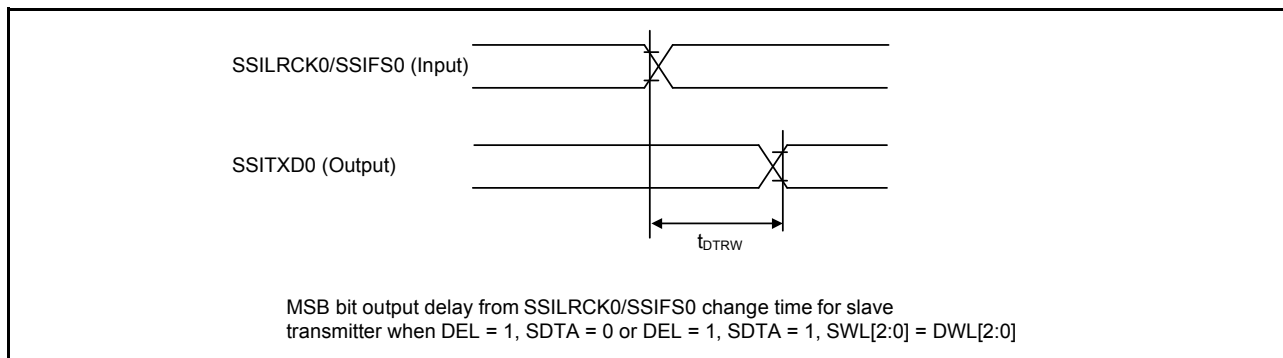


Figure 2.74 SSIE data output delay from SSILRCK0/SSIFS0 change time

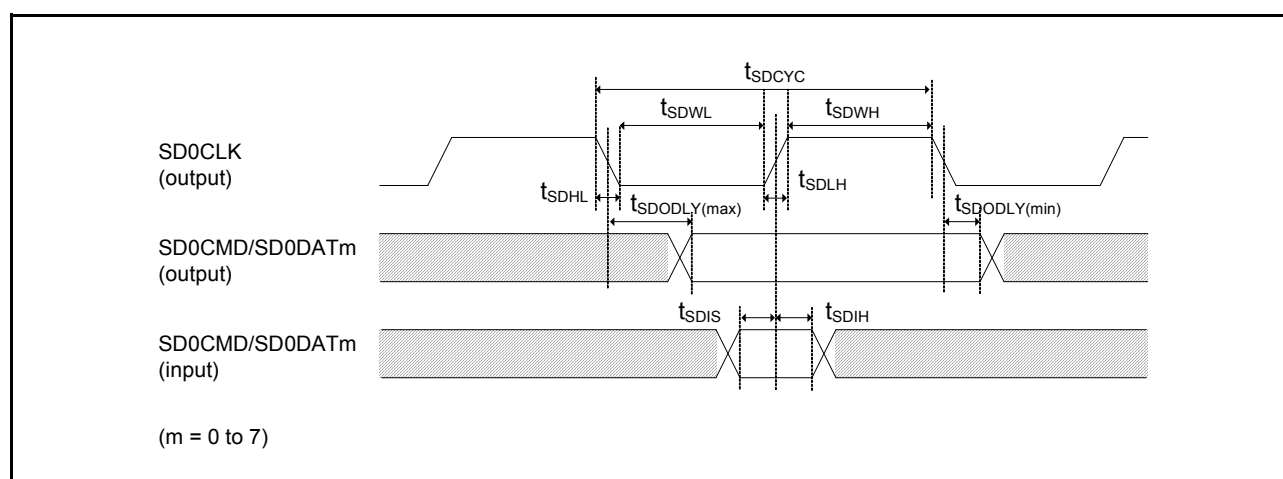
2.3.14 SD/MMC Host Interface Timing

Table 2.44 SD/MMC host interface signal timing

Conditions: VCC = 2.7 to 5.5 V

Middle drive output is selected in the Port Drive Capability in PmnPFS register

Parameter	Symbol	Min	Max	Unit	Test conditions
SDCLK clock cycle	t_{SDCYC}	62.5	-	ns	Figure 2.75
SDCLK clock high-level pulse width	t_{SDWH}	18.25	-	ns	
SDCLK clock low-level pulse width	t_{SDWL}	18.25	-	ns	
SDCLK clock rising time	t_{SDLH}	-	10	ns	
SDCLK clock falling time	t_{SDHL}	-	10	ns	
SDCMD/SDDAT output data delay	t_{SDODLY}	-18.25	18.25	ns	
SDCMD/SDDAT input data setup	t_{SDIS}	9.25	-	ns	
SDCMD/SDDAT input data hold	t_{SDIH}	23.25	-	ns	

**Figure 2.75 SD/MMC host interface signal timing**

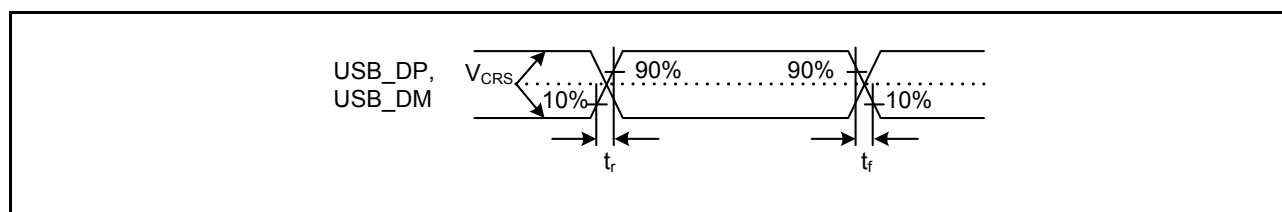
2.4 USB Characteristics

2.4.1 USBFS Timing

Table 2.46 USB characteristics

Conditions: $V_{CC} = V_{CC_USB} = 3.0$ to 3.6 V, $T_a = -20$ to $+85^\circ\text{C}$ (USBCLKSEL = 1), $T_a = -40$ to $+105^\circ\text{C}$ (USBCLKSEL = 0)

Parameter		Symbol	Min	Max	Unit	Test conditions	
Input characteristics	Input high level voltage	V _{IH}	2.0	-	V	-	
	Input low level voltage	V _{IL}	-	0.8	V	-	
	Differential input sensitivity	V _{DI}	0.2	-	V	USB_DP - USB_DM	
	Differential common mode range	V _{CM}	0.8	2.5	V	-	
Output characteristics	Output high level voltage	V _{OH}	2.8	VCC_USB	V	I _{OH} = −200 μA	
	Output low level voltage	V _{OL}	0.0	0.3	V	I _{OL} = 2 mA	
	Cross-over voltage		V _{CRS}	1.3	2.0	V	Figure 2.77, Figure 2.78, Figure 2.79
	Rise time	FS	t _r	4	20	ns	
		LS		75	300		
	Fall time	FS	t _f	4	20	ns	
		LS		75	300		
	Rise/fall time ratio	FS	t _r /t _f	90	111.11	%	
		LS		80	125		
	Output resistance		Z _{DRV}	28	44	Ω	(Adjusting the resistance of external elements is not required.)
VBUS characteristics	VBUS input voltage	V _{IH}	VCC × 0.8	-	V	-	
		V _{IL}	-	VCC × 0.2	V	-	
Pull-up, pull-down	Pull-down resistor	R _{PD}	14.25	24.80	kΩ	-	
	Pull-up resistor	R _{PUI}	0.9	1.575	kΩ	During idle state	
		R _{PUA}	1.425	3.09	kΩ	During reception	
Battery Charging Specification Ver 1.2	D+ sink current	I _{DP_SINK}	25	175	μA	-	
	D− sink current	I _{DM_SINK}	25	175	μA	-	
	DCD source current	I _{DP_SRC}	7	13	μA	-	
	Data detection voltage	V _{DAT_REF}	0.25	0.4	V	-	
	D+ source voltage	V _{DP_SRC}	0.5	0.7	V	Output current = 250 μA	
	D− source voltage	V _{DM_SRC}	0.5	0.7	V	Output current = 250 μA	


Figure 2.77 USB_DP and USB_DM output timing

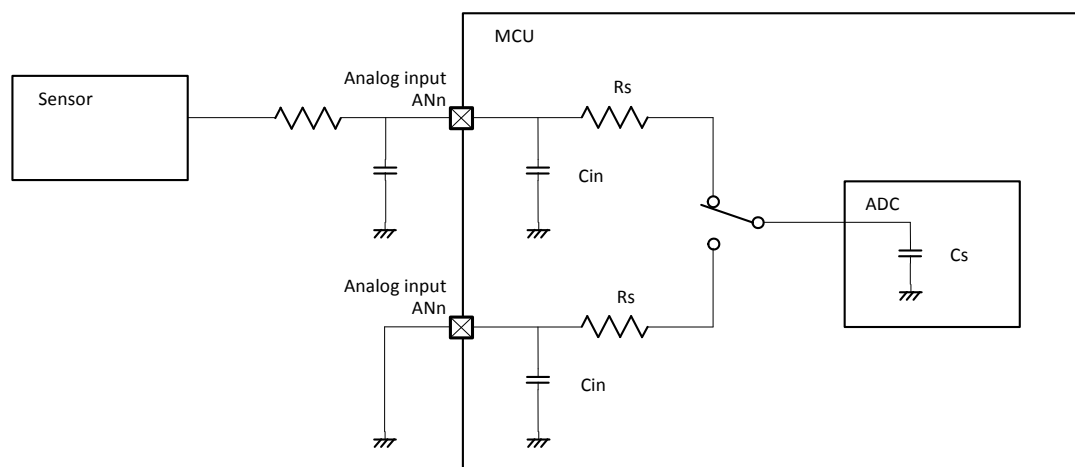


Figure 2.81 Equivalent circuit for analog input

Table 2.55 14-bit A/D converter channel classification

Classification	Channel	Conditions	Remarks
High-precision channel	AN000 to AN015	AVCC0 = 1.6 to 5.5 V	Pins AN000 to AN015 cannot be used as general I/O, IRQ2, IRQ3 inputs, and TS transmission, when the A/D converter is in use
Normal-precision channel	AN016 to AN027		
Internal reference voltage input channel	Internal reference voltage	AVCC0 = 2.0 to 5.5 V	-
Temperature sensor input channel	Temperature sensor output	AVCC0 = 2.0 to 5.5 V	-

Table 2.56 A/D internal reference voltage characteristics

Conditions: VCC = AVCC0 = VREFH0 = 2.0 to 5.5 V*1

Parameter	Min	Typ	Max	Unit	Test conditions
Internal reference voltage input channel*2	1.36	1.43	1.50	V	-
Frequency*3	1	-	2	MHz	-
Sampling time*4	5.0	-	-	μs	-

Note 1. The internal reference voltage cannot be selected for input channels when AVCC0 < 2.0 V.

Note 2. The 14-bit A/D internal reference voltage indicates the voltage when the internal reference voltage is input to the 14-bit A/D converter.

Note 3. This is a parameter for ADC14 when the internal reference voltage is used as the high-potential reference voltage.

Note 4. This is a parameter for ADC14 when the internal reference voltage is selected for an analog input channel in ADC14.

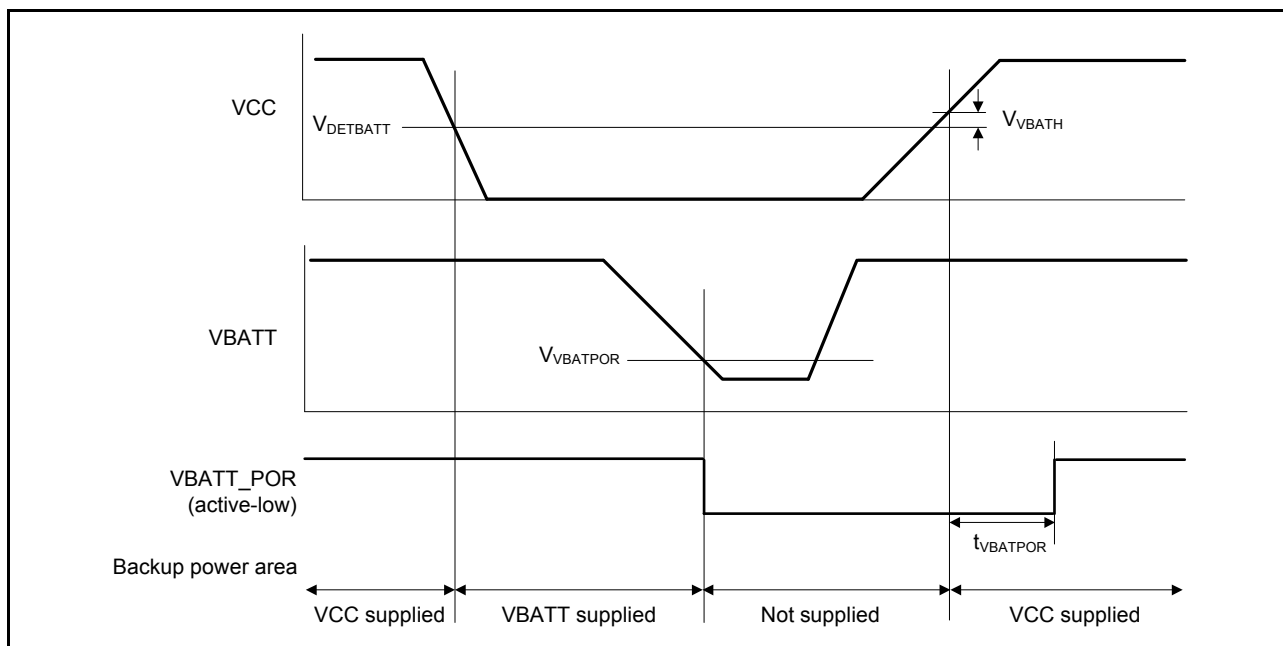


Figure 2.91 VBATT_POR reset timing

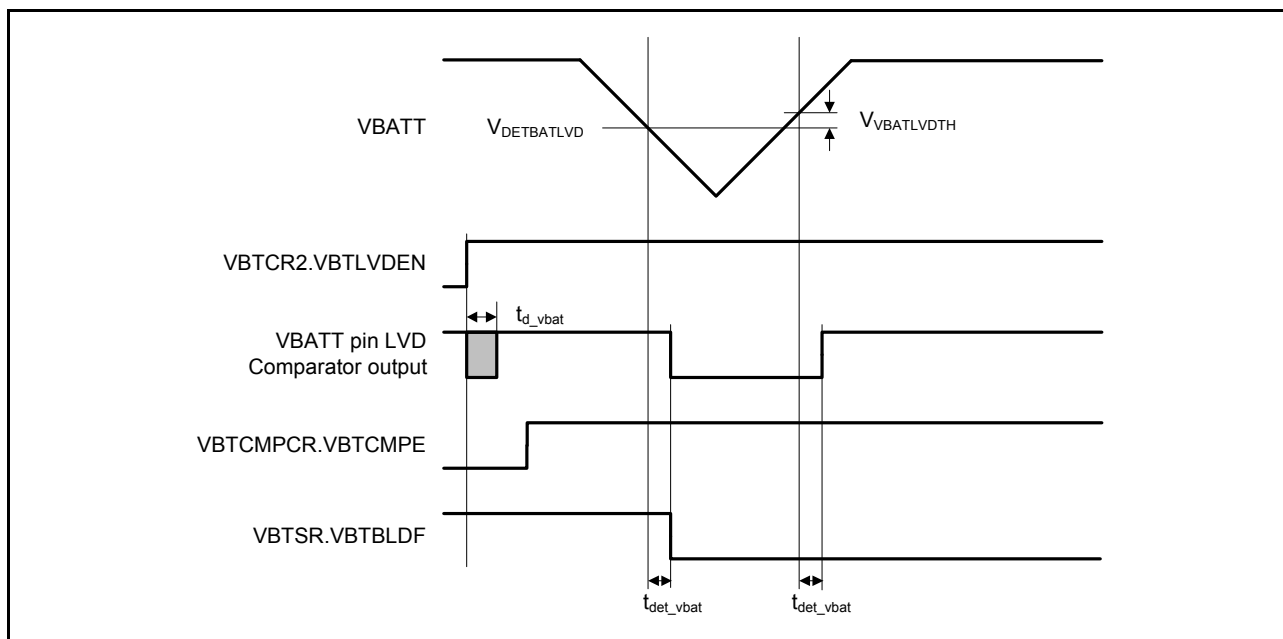


Figure 2.92 VBATT pin voltage detection circuit timing

Appendix 1. Package Dimensions

Information on the latest version of the package dimensions or mountings is displayed in “Packages” on the Renesas Electronics Corporation website.

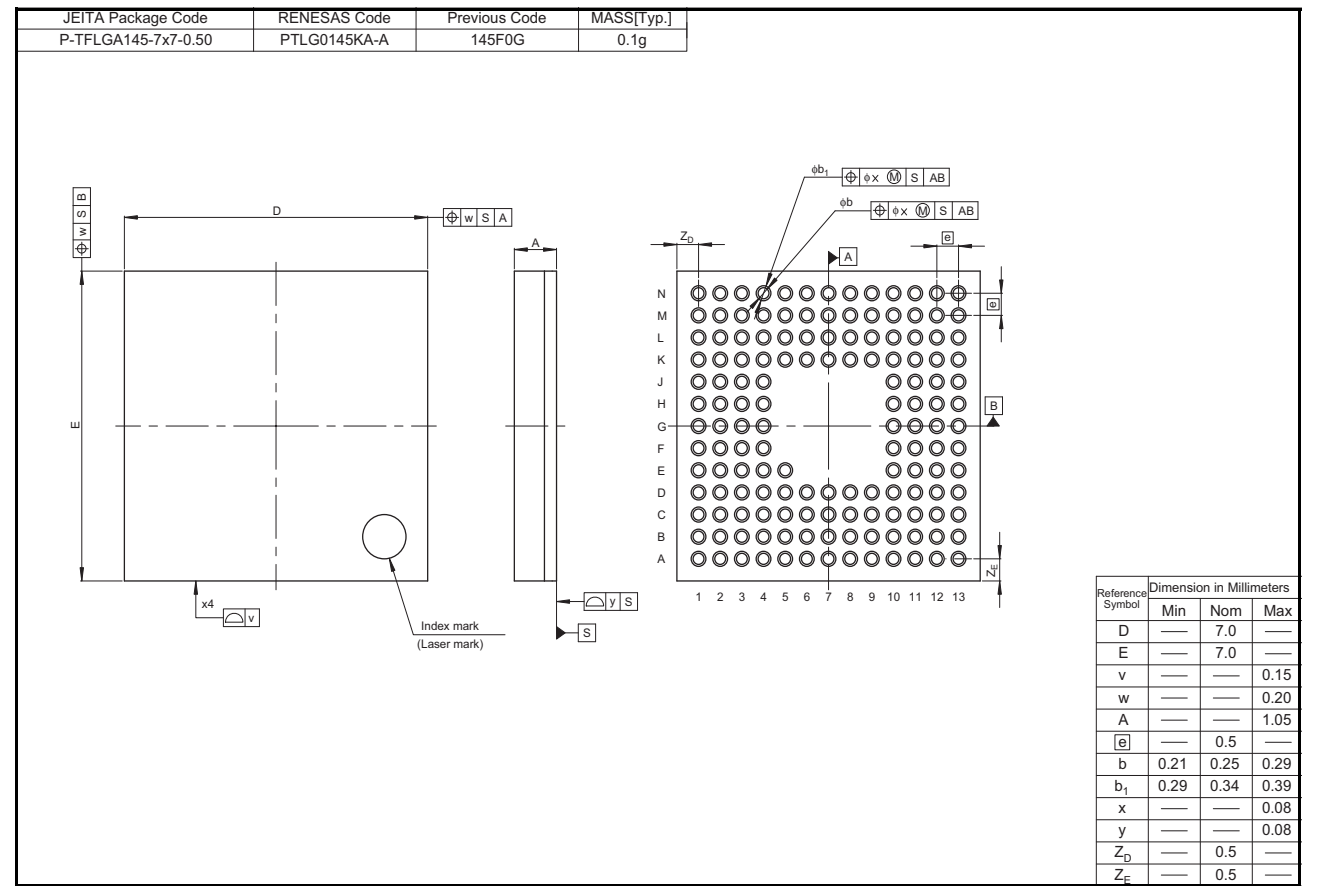


Figure 1.1 LGA 145-pin

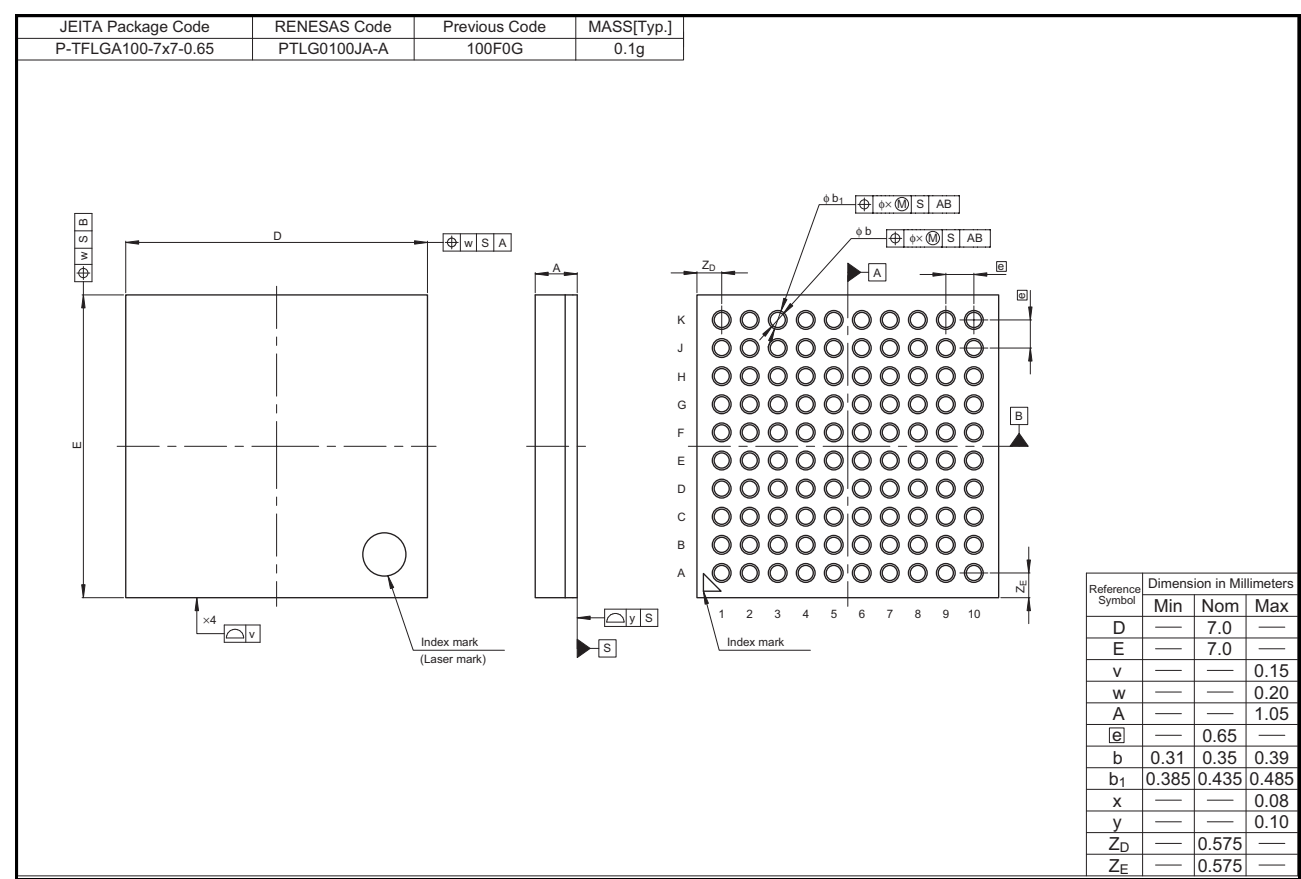


Figure 1.4 LGA 100-pin

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